



# 20th International Workshop on DEPFET Detectors and Applications

## Thursday, 12 May 2016

### PXD9 Pilot run, Sensor Testing - Tagungsraum (11:00 - 12:00)

-Conveners: Rainer Richter

time	[id] title	presenter
11:00	[71] Yield measurements on PXD9-7 after 2nd Metal	Mr KLOSE, Daniel
11:25	[72] PXD9-7 failure analysis with Light Emission Microscope (PHEMOS)	NINKOVIC, Jelena
11:40	[73] PXD9-7 Metal 2 repair and PXD9 production overview	RICHTER, Rainer